IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/736,386)	6227
Filed:	December 15, 2003))	0221
Title:	METHOD FOR CALCULATING HIGH-RESOLUTION WAFER PARAMETER PROFILES)))	
Inventors:	Bruce Whitefield et al.))	
Art Unit:	2128))	
Examiner:	Kimberly A. Thornwell))	
Atty. Ref:	03-1345	<i>)</i>)	

RESPONSE TO THE OFFICE ACTION MAILED JULY 30, 2007

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed July 30, 2007, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application. A Petition for Extension of Time is enclosed, extending the deadline for responding to the Office Action to November 30, 2007. Therefore, this Response is considered timely.